

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination YOSHIHARA ET AL.	
		Examiner Hai V. Nguyen	Art Unit 2142	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,423,893	07-2002	Sung et al.	84/645
	B	US-6,161,132	12-2000	Roberts et al.	709/219
	C	US-6,057,503	05-2000	Shinsky, Jeff K.	84/657
	D	US-6,156,965	12-2000	Shinsky, Jeff K.	84/650
	E	US-6,156,966	12-2000	Shinsky, Jeff K.	84/657
	F	US-5,046,004	09-1991	Tsumura et al.	84/601
	G	US-5,734,119	03-1998	France et al.	84/622
	H	US-RE38,554	07-2004	Ide, Kensuke	84/622
	I	US-6,518,491	02-2003	Kurakake et al.	84/610
	J	US-6,525,253	02-2003	Kikuchi et al.	84/601
	K	US-6,686,531	02-2004	Pennock et al.	84/615
	L	US-6,835,884	12-2004	Iwamoto et al.	84/609
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.